

Tester Patterns and Diagnostics

The Synopsys SLM SMS IP Yield Accelerator addresses the need to identify, analyze, isolate, and classify memory faults as designs are readied for transition from first silicon to volume manufacturing rapidly, cost-effectively and accurately. Leveraging the infrastructure of the Synopsys SLM SMS IP, the Yield Accelerator automatically generates vectors for test equipment and provides fault analysis and root-cause failure guidance based on silicon test results. Using this feature, test and product engineers can rapidly analyze failures manifested in embedded memories and inspect the physical location and class of each fault to determine the root cause in the manufacturing and development of designs.